



EXPRESS MAIL LABEL NO. EV016318321US

PATENT APPLICATION
Docket No: 11675.168.1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of Leonard E. Mess)
Serial No. 09/501,033)
Filed: February 9, 2000)Art Unit 2858
For: SYSTEM FOR TESTING A)
SEMICONDUCTOR DEVICE)
Examiner: Vinh P. Nguyen)
Confirmation No.: 3325)

PROPOSED DRAWING CORRECTIONS

The Assistant Commissioner of Patents
and Trademarks
Washington, D. C. 20231
Sir:

Please add Figs. 10, 11 and 12 as shown in the accompanying sheet. Support for these figures is found in the Application as filed, for example, at p. 11, 4-15, and p. 13, 11. 7-16.

In the event that the Examiner encounters an issue which could be clarified by a telephonic interview, the Examiner is respectfully requested to initiate the same with the undersigned attorney.

DATED this 24th day of January, 2002.

Respectfully submitted,

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Amendment "D" and Response / Proposed Drawings
Serial No. 09/501,033

**Title: SYSTEM FOR TESTING A
SEMICONDUCTOR DEVICE**

Applicant: Leonard E. Mess

Serial No.: 09/501,033

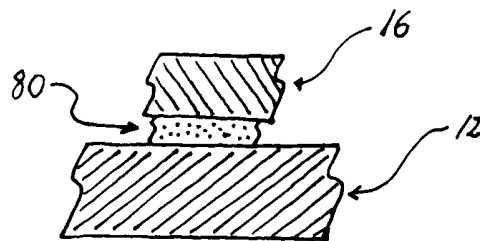


Fig. 10

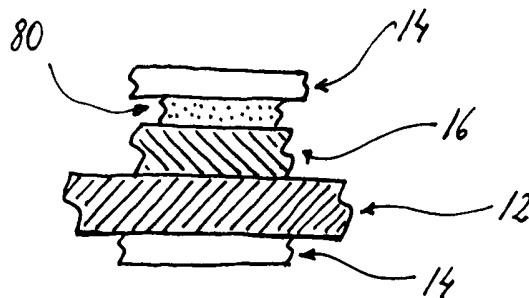


Fig. 11

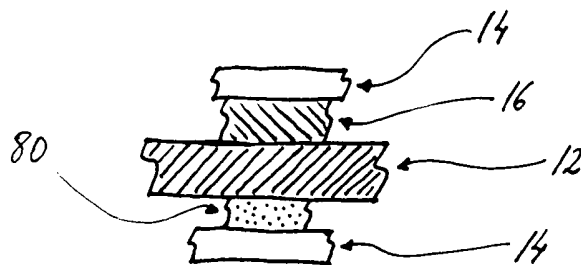


Fig. 12

Title: SYSTEM FOR TESTING A
SEMICONDUCTOR DEVICE

Applicant: Leonard E. Mess

Serial No.: 09/501,033

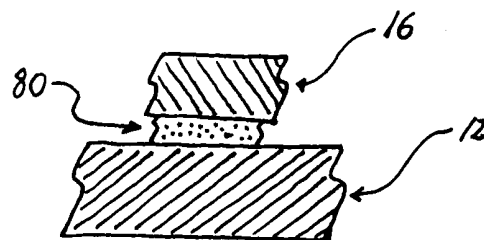


Fig. 10

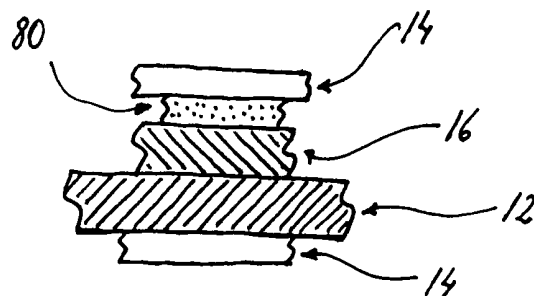


Fig. 11

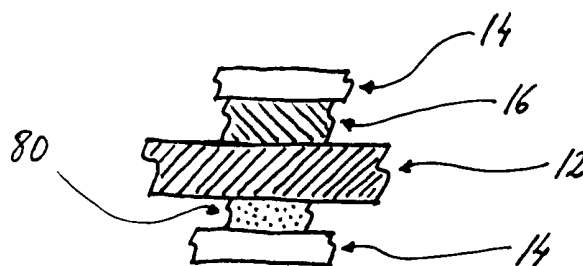


Fig. 12